

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1784	"714"/\$.ccls. and ((test testing analysing analyzing analysis) with ((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj erasable adj programmable adj read adj only adj memory) ((electrical electronic erasable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array)))	US-PGPUB; USPAT	OR	ON	2005/05/02 08:32
L2	5	"714"/\$.ccls. and ((test testing analysing analyzing analysis) with ((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj erasable adj programmable adj read adj only adj memory) ((electrical electronic erasable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array))) and ((store storage save saving record recording cache caching storing) with ((first initial primary) near4 (test testing analysing analyzing analysis) near3 (data information))) and judg\$5 and (defective faulty flawed) and ((store storage save saving record recording cache caching storing) with ((second later secondary subsequent following) near4 (test testing analysing analyzing analysis) near3 (data information)))	US-PGPUB; USPAT	OR	ON	2005/05/02 07:30
L3	1	714/718.ccls. and ((non\$volatile adj memory) same (judge judging judgement judging judged determine determined determining determination) same (defect defective anomaly anomolous abnormal abnormality flaw flawed faulty fault fail failing failure failed flawed faulted) same ((first initial primary prior previous second secondary subsequent following later) near3 (test testing) near3 (data information)))	US-PGPUB; USPAT	OR	ON	2005/05/02 07:37
L4	0	714/718.ccls. and ((non\$volatile adj memory) same (judge judging judgement judging judged determine determined determining determination) same (defect defective anomaly anomolous abnormal abnormality flaw flawed faulty fault fail failing failure failed flawed faulted) same (first initial primary prior previous) same (second secondary subsequent following later) same ((test testing) near3 (data information)))	US-PGPUB; USPAT	OR	ON	2005/05/02 08:27

L5	0	714/336.ccls.	US-PGPUB; USPAT	OR	OFF	2005/05/02 08:27
L6	0	714/336.ccls.	US-PGPUB; USPAT	OR	OFF	2005/05/02 08:30
L7	197	714/36.ccls.	US-PGPUB; USPAT	OR	OFF	2005/05/02 08:30
L8	30103	"714"/\$.ccls. and (stor\$3 first test data memory judg\$5 defective) and (stor\$3 second test data)	US-PGPUB; USPAT	OR	ON	2005/05/02 09:50
L9	1	"714"/\$.ccls. and ((stor\$3 with first with test with data with memory) same judg\$5 same defective) and (stor\$3 with second with test with data)	US-PGPUB; USPAT	OR	ON	2005/05/02 10:05
L10	1	"714"/\$.ccls. and ((second with test with step with storing) same (judged with defective with first with test with step) same (replacing with first with test with data with second) same (testing with using with second with test with data))	US-PGPUB; USPAT	OR	ON	2005/05/02 10:08
L11	1	(non\$volatile adj memory) and ((second with test with step with storing) same (judged with defective with first with test with step) same (replacing with first with test with data with second) same (testing with using with second with test with data))	US-PGPUB; USPAT	OR	ON	2005/05/02 10:08
L12	0	(non\$volatile adj memory) and ((second with test with step with storing) same (judged with defective with first with test with step) same (replacing with first with test with data with second) same (testing with using with second with test with data))	USOCR; IBM_TDB	OR	ON	2005/05/02 10:09
L13	0	(non\$volatile adj memory) and ((second with test with step with storing) same (judged with defective with first with test with step) same (replacing with first with test with data with second) same (testing with using with second with test with data))	EPO; JPO; DERWENT	OR	ON	2005/05/02 10:10
L14	667	714/736.ccls.	US-PGPUB; USPAT	OR	OFF	2005/05/02 10:10
L15	1	714/736.ccls. and judg\$5 and defective and (first adj test\$3) and (second adj test\$3)	US-PGPUB; USPAT	OR	ON	2005/05/02 10:11
L16	6	714/736.ccls. and judg\$5 and defective and (first with test\$3) and (second with test\$3)	US-PGPUB; USPAT	OR	ON	2005/05/02 10:14
L17	0	714/736.ccls. and judg\$5 same memory same defective and (first with (test\$3 near3 (step event occurrence item iteration))) and (second with (test\$3 near3 (step event occurrence item iteration)))	US-PGPUB; USPAT	OR	ON	2005/05/02 10:17

L18	0	714/736.ccls. and judg\$5 same memory same defective and (first with test\$3 with (step event occurrence item iteration)) and (second with test\$3 with (step event occurrence item iteration))	US-PGPUB; USPAT	OR	ON	2005/05/02 10:18
L19	0	714/736.ccls. and (judg\$5 same memory same defective and (first with test\$3 with (step event occurrence item iteration)) and (second with test\$3 with (step event occurrence item iteration)))	US-PGPUB; USPAT	OR	ON	2005/05/02 10:18
L20	0	714/736.ccls. and judg\$5 and memory and defective and ((first with test\$3 with (step event occurrence item iteration)) and (second with test\$3 with (step event occurrence item iteration)))	US-PGPUB; USPAT	OR	ON	2005/05/02 10:18
S1	1	"20040153924".pn.	US-PGPUB	OR	OFF	2005/05/02 07:18
S2	340	shinagawa.in.	US-PGPUB; USPAT	OR	OFF	2005/04/20 12:52
S3	1541	kawahara.in.	US-PGPUB; USPAT	OR	OFF	2005/04/20 12:47
S4	2998	fukushima.in.	US-PGPUB; USPAT	OR	OFF	2005/04/20 12:47
S5	905	kurata.in.	US-PGPUB; USPAT	OR	OFF	2005/04/20 12:47
S6	736	komiya.in.	US-PGPUB; USPAT	OR	OFF	2005/04/20 12:47
S7	1	shinagawa.in. and kawahara.in. and fukushima.in. and kurata.in. and komiya.in.	US-PGPUB; USPAT	OR	OFF	2005/04/20 12:47
S8	2	shinagawa.in. and kawahara.in. and fukushima.in. and kurata.in. and komiya.in.	EPO; JPO; DERWENT	OR	OFF	2005/04/20 12:47
S9	2865	shinagawa.in.	US-PGPUB; EPO; JPO; DERWENT	OR	OFF	2005/04/20 12:47
S10	12464	kawahara.in.	EPO; JPO; DERWENT	OR	OFF	2005/04/20 12:47
S11	23741	fukushima.in.	EPO; JPO; DERWENT	OR	OFF	2005/04/20 12:47
S12	7306	kurata.in.	EPO; JPO; DERWENT	OR	OFF	2005/04/20 12:47
S13	4945	komiya.in.	EPO; JPO; DERWENT	OR	OFF	2005/04/20 12:49
S14	1363	(computer micro\$computer) and (micro\$chip micro\$ircuit) and (non\$volatile adj memory)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 12:53

S15	782	(computer micro\$computer) and (micro\$chip micro\$circuit) and (non\$volatile adj memory) and (cpu (central adj processing adj unit))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 12:54
S16	32	(computer micro\$computer) and (micro\$chip micro\$circuit) and (non\$volatile adj memory) and (cpu (central adj processing adj unit)) and (memory adj control\$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 12:55
S17	5	(computer micro\$computer) and (micro\$chip micro\$circuit) and (non\$volatile adj memory) and (cpu (central adj processing adj unit)) and (memory adj control\$2) and (drive adj (unit section module component))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 13:33
S18	0	(computer micro\$computer) and (micro\$chip micro\$circuit) and (non\$volatile adj memory) and (cpu (central adj processing adj unit)) and (memory adj control\$2) and (drive adj (unit section module component)) and (output adj (unit section module component))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 12:56
S19	572	700/90.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:33
S20	473	700/95.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:33
S21	518	700/108.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:33
S22	257	700/109.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:33
S23	349	700/110.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:34
S24	467	700/117.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:34
S25	1225	700/121.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:34
S26	541	702/117.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:34
S27	221	702/118.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:34
S28	204	702/119.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:34
S29	202	702/120.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:34
S30	901	702/182.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:34

S31	749	702/183.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:34
S32	568	702/189.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:34
S33	496	702/for "135".ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:37
S34	23	702/118.ccls. and 702/for "135".ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 15:26
S35	45	702/118.ccls. and 702/117.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:38
S36	26	702/118.ccls. and 702/119.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:38
S37	27	702/118.ccls. and 702/120.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:39
S38	7	702/118.ccls. and 702/182.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:38
S39	7	702/118.ccls. and 702/183.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:38
S40	3	702/118.ccls. and 702/189.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:38
S41	0	702/118.ccls. and 700/90.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:39
S42	0	702/118.ccls. and 700/95.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:39
S43	1	702/118.ccls. and 700/108.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:40
S44	3	702/118.ccls. and 700/109.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 15:32
S45	6	702/118.ccls. and 700/110.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:40
S46	1	702/118.ccls. and 700/117.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:40
S47	10	702/118.ccls. and 700/121.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:40
S48	0	702/118.ccls. and 710/1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:40
S49	2	702/118.ccls. and 714/100.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:41
S50	1005	710/1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:41
S51	75	714/100.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 13:41
S52	1	micro\$computer and ((plural several many plurality multiple) near3 (circuit adj (block section region area))) and (non\$volatile adj memory) and (memory adj control adj (unit section module)) and (drive adj (unit section module)) and (output adj (unit section module))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 13:47

S53	1	micro\$computer and ((plural several many plurality multiple) near3 (circuit adj (block section region area))) and (non\$volatile adj memory) and (memory adj control adj (unit section module)) and (drive adj (unit section module))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 13:47
S54	2	micro\$computer and ((plural several many plurality multiple) near3 (circuit adj (block section region area))) and (non\$volatile adj memory) and (memory adj control adj (unit section module))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 13:48
S55	32	micro\$computer and ((plural several many plurality multiple) near3 (circuit adj (block section region area))) and (non\$volatile adj memory)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 13:51
S56	8074	micro\$computer and (non\$volatile adj memory)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 13:52
S57	318	micro\$computer and ((test\$3 analysing analyzing analysis) with (non\$volatile adj memory))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 13:53
S58	37	micro\$computer and ((test\$3 analysing analyzing analysis) with (non\$volatile adj memory)) and ((drive driver) adj (unit section module block circuit buffer))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 13:59
S59	18	micro\$computer and ((test\$3 analysing analyzing analysis) with (non\$volatile adj memory)) and ((drive driver driving) adj (unit section module block circuit buffer)) and ((output outputting) adj (unit section module block circuit buffer))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 14:02
S60	53	micro\$computer and ((test\$3 analysing analyzing analysis) with ((non\$volatile flash eeprom) adj memory)) and ((drive driver driving) adj (unit section module block circuit buffer)) and ((output outputting) adj (unit section module block circuit buffer))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 14:07

S61	423	(micro\$computer micro\$processor) and ((test\$3 analysing analyzing analysis) with ((rom eprom eeprom earom (read adj only adj memory) (electrical adj programmable adj read adj only adj memory) (electrically adj eraseable adj programmable adj read adj only adj memory) (electrically adj alterable adj programmable adj read adj only adj memory) ((non\$volatile flash eeprom) adj memory)))) and ((drive driver driving) adj (unit section module block circuit buffer)) and ((output outputting) adj (unit section module block circuit buffer))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 14:18
S62	220	(micro\$computer micro\$processor) and ((test\$3 analysing analyzing analysis) near5 ((rom eprom eeprom earom (read adj only adj memory) (electrical adj programmable adj read adj only adj memory) (electrically adj eraseable adj programmable adj read adj only adj memory) (electrically adj alterable adj programmable adj read adj only adj memory) ((non\$volatile flash eeprom) adj memory)))) and ((drive driver driving) adj (unit section module block circuit buffer)) and ((output outputting) adj (unit section module block circuit buffer))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 15:12
S63	529	(micro\$computer micro\$processor) and (address adj generation adj (unit section circuit module)) and ((rom eprom eeprom earom (read adj only adj memory) (electrical adj programmable adj read adj only adj memory) (electrically adj eraseable adj programmable adj read adj only adj memory) (electrically adj alterable adj programmable adj read adj only adj memory) ((non\$volatile flash eeprom) adj memory))))	US-PGPUB; USPAT	OR	ON	2005/04/20 14:31
S64	105	(micro\$computer micro\$processor) and (address adj generation adj (unit section circuit module)) and ((rom eprom eeprom earom (read adj only adj memory) (electrical adj programmable adj read adj only adj memory) (electrically adj eraseable adj programmable adj read adj only adj memory) (electrically adj alterable adj programmable adj read adj only adj memory) ((non\$volatile flash eeprom) adj memory)))) and ((drive driver driving) adj (unit section circuit module))	US-PGPUB; USPAT	OR	ON	2005/04/20 14:36

S65	13	(micro\$computer micro\$processor) and (address adj generation adj (unit section circuit module)) and ((rom eeprom eeprom earom (read adj only adj memory) (electrical adj programmable adj read adj only adj memory) (electrically adj erasable adj programmable adj read adj only adj memory) (electrically adj alterable adj programmable adj read adj only adj memory) ((non\$volatile flash eeprom) adj memory))) and ((drive driver driving) adj (unit section circuit module)) and (memory adj (control controller controlling) adj (unit section circuit module))	US-PGPUB; USPAT	OR	ON	2005/04/20 14:32
S66	3642	(micro\$computer micro\$processor) and ((rom eeprom eeprom earom (read adj only adj memory) (electrical adj programmable adj read adj only adj memory) (electrically adj erasable adj programmable adj read adj only adj memory) (electrically adj alterable adj programmable adj read adj only adj memory) ((non\$volatile flash eeprom) adj memory))) and ((drive driver driving) adj (unit section circuit module)) and ((output outputting) adj (unit section circuit module))	US-PGPUB; USPAT	OR	ON	2005/04/20 14:37
S67	357	(micro\$computer micro\$processor) and ((rom eeprom eeprom earom (read adj only adj memory) (electrical adj programmable adj read adj only adj memory) (electrically adj erasable adj programmable adj read adj only adj memory) (electrically adj alterable adj programmable adj read adj only adj memory) ((non\$volatile flash eeprom) adj memory))) and ((drive driver driving) adj (unit section circuit module)) and ((output outputting) adj (unit section circuit module)) and (test\$3 adj (signal data information))	US-PGPUB; USPAT	OR	ON	2005/04/20 14:39
S68	172	(micro\$computer micro\$processor) and ((rom eeprom eeprom earom (read adj only adj memory) (electrical adj programmable adj read adj only adj memory) (electrically adj erasable adj programmable adj read adj only adj memory) (electrically adj alterable adj programmable adj read adj only adj memory) ((non\$volatile flash eeprom) adj memory))) and ((drive driver driving) adj (unit section circuit module)) and ((output outputting) adj (unit section circuit module)) and (test\$3 adj (signal data information)) and (circuit adj (block section region area))	US-PGPUB; USPAT	OR	ON	2005/04/20 14:40

S69	7	(micro\$computer micro\$processor) and ((rom eeprom eeprom earom pga fpga (programmable adj gate adj array) (field adj programmable adj gate adj array)(read adj only adj memory) (electrical adj programmable adj read adj only adj memory) (electrically adj eraseable adj programmable adj read adj only adj memory) (electrically adj alterable adj programmable adj read adj only adj memory) ((non\$volatile flash eeprom) adj memory))) and ((drive driver driving) adj (unit section circuit module)) and ((output outputting) adj (unit section circuit module)) and (test\$3 adj (signal data information)) and ((plural several plurality many multiple) near3 (circuit adj (block section region area)))	US-PGPUB; USPAT	OR	ON	2005/04/20 15:13
S70	0	(micro\$computer micro\$processor) and ((rom eeprom eeprom earom pga fpga (programmable adj gate adj array) (field adj programmable adj gate adj array)(read adj only adj memory) (electrical adj programmable adj read adj only adj memory) (electrically adj eraseable adj programmable adj read adj only adj memory) (electrically adj alterable adj programmable adj read adj only adj memory) ((non\$volatile flash eeprom) adj memory))) and ((drive driver driving) adj (unit section circuit module)) and ((output outputting) adj (unit section circuit module)) and (test\$3 adj (signal data information)) and ((plural several plurality many multiple) near3 (circuit adj (block section region area)))	USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/20 15:13
S71	1	"5450576".pn.	USPAT	OR	OFF	2005/04/20 15:26
S72	1	702/118.ccls. and "713"/\$.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 15:27
S73	6	702/117.ccls. and "713"/\$.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 15:27
S74	1610	713/1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 15:31
S75	0	702/118.ccls. and 713/1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 15:32
S76	2	702/117.ccls. and 713/1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/20 15:32
S77	1	"4519078".pn.	USPAT	OR	OFF	2005/04/21 06:44
S78	77	("4519078").URPN.	USPAT	OR	OFF	2005/04/21 06:45

S79	25	("4519078").URPN. and ((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory))	USPAT	OR	ON	2005/04/21 06:49
S80	0	("4519078").URPN. and ((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory)) and ((drive driver driving) adj (circuit unit module section part))	USPAT	OR	ON	2005/04/21 06:50
S81	0	("4519078").URPN. and ((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array)) and ((memory register cache) adj (control controlling controller) adj (circuit unit module section part))	USPAT	OR	ON	2005/04/21 06:51
S82	25	("4519078").URPN. and ((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array))	USPAT	OR	ON	2005/04/21 07:02
S83	15	("4680761").URPN.	USPAT	OR	OFF	2005/04/21 06:58
S84	65	("4764926").URPN.	USPAT	OR	OFF	2005/04/21 06:58
S85	12	("5371748").URPN.	USPAT	OR	OFF	2005/04/21 06:58
S86	57	("5617531").URPN.	USPAT	OR	OFF	2005/04/21 07:01

S87	62	(S83 S84 S85 S86) and ((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array))	USPAT	OR	ON	2005/04/21 07:08
S88	15	(S83 S84 S85 S86) and ((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array)) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section))	USPAT	OR	ON	2005/04/21 07:14
S89	30	(S83 S84 S85 S86) and ((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array)) and (lsi (large adj scale adj integration) micro\$computer micro\$processor)	USPAT	OR	ON	2005/04/21 07:09
S90	7	("5936900").URPN.	USPAT	OR	OFF	2005/04/21 07:13
S91	1824	((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array)) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit))	USPAT	OR	ON	2005/04/21 07:15

S92	1099	((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array)) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit)) and (micro\$computer micro\$processor))	USPAT	OR	ON	2005/04/21 07:16
S93	59	((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array)) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit)) and (micro\$computer micro\$processor) and (memory adj (control controller controlling) adj (unit section part module)))	USPAT	OR	ON	2005/04/21 07:17
S94	22	((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array)) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit)) and (micro\$computer micro\$processor) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)))	USPAT	OR	ON	2005/04/21 07:22

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S95	1	((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) pga (programmable adj gate adj array)) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit)) and (micro\$computer micro\$processor) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)) and ((output outputting) adj (unit section part module)))	USPAT	OR	ON	2005/04/21 07:18
S96	6	((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) cdrom (compact adj (disc disk) adj read adj only adj memory)) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit)) and (micro\$computer micro\$processor pga (programmable adj gate adj array)) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)) and ((test\$3 expectation) adj (data signal information waveform)))	USPAT	OR	ON	2005/04/21 07:26

S97	0	((non\$volatile adj memory) (read adj only adj memory) ((electrical electronic) adj eraseable adj programmable adj read adj only adj memory) ((electrical electronic eraseable) adj programmable adj read adj only adj memory) (programmable adj read adj only adj memory) rom eprom prom eeprom (flash adj memory) cdrom (compact adj (disc disk) adj read adj only adj memory)) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit)) and (micro\$computer micro\$processor pga (programmable adj gate adj array)) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)) and ((test\$3 expectation) adj (data signal information waveform)) and judg\$5	USPAT	OR	ON	2005/04/21 07:28
S98	0	microcomputer and (non\$volatile adj memory) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit)) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)) and ((output outputting) adj (unit section part module)) and ((test testing) adj (signal waveform data information))	USPAT	OR	ON	2005/04/21 07:31
S99	1	microcomputer and (non\$volatile adj memory) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit)) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)) and ((output outputting) adj (unit section part module)) and ((test testing) adj (signal waveform data information))	US-PGPUB	OR	ON	2005/04/21 07:31
S100	0	microcomputer and (non\$volatile adj memory) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit)) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)) and ((output outputting) adj (unit section part module)) and ((test testing) adj (signal waveform data information))	IBM_TDB	OR	ON	2005/04/21 07:31

S101	0	microcomputer and (non\$volatile adj memory) and ((plural several many multiple plurality) near3 circuit near3 (block device unit module section)) and (cpu (central adj (processor processing) adj unit)) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)) and ((output outputting) adj (unit section part module)) and ((test testing) adj (signal waveform data information))	EPO; JPO; DERWENT	OR	ON	2005/04/21 07:32
S102	0	microcomputer and (non\$volatile adj memory) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)) and ((output outputting) adj (unit section part module)) and ((test testing) adj (signal waveform data information))	EPO; JPO; DERWENT	OR	ON	2005/04/21 07:32
S103	1	microcomputer and (non\$volatile adj memory) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)) and ((output outputting) adj (unit section part module)) and ((test testing) adj (signal waveform data information))	US-PGPUB	OR	ON	2005/04/21 07:32
S104	0	microcomputer and (non\$volatile adj memory) and (memory adj (control controller controlling) adj (unit section part module)) and ((driver driving drive) adj (unit section part module)) and ((output outputting) adj (unit section part module)) and ((test testing) adj (signal waveform data information))	USPAT	OR	ON	2005/04/21 07:33
S105	0	(memory adj tester) and ((test testing) adj (signal data information waveform)) and (expectation adj (signal data information)) and (non\$volatile adj memory) and (circuit adj (block section part)) and ((judge judgement judging) with (quality performance operation function))	USPAT	OR	ON	2005/04/21 07:36
S106	0	(memory adj tester) and ((test testing) adj (signal data information waveform)) and (expectation adj (signal data information)) and (non\$volatile adj memory) and (circuit adj (block section part)) and ((judge judgement judging) with (quality performance operation function))	US-PGPUB	OR	ON	2005/04/21 07:36

S107	0	(memory adj tester) and ((test testing) adj (signal data information waveform)) and (expectation adj (signal data information)) and (non\$volatile adj memory) and (circuit adj (block section part)) and ((judge judgement judging) with (quality performance operation function))	EPO; JPO; DERWENT	OR	ON	2005/04/21 07:37
S108	0	(memory adj tester) and ((test testing) adj (signal data information waveform)) and (expectation adj (signal data information)) and (non\$volatile adj memory) and (circuit adj (block section part)) and ((judge judgement judging) with (quality performance operation function))	IBM_TDB	OR	ON	2005/04/21 07:37
S109	0	(memory adj tester) and ((test testing) adj (signal data information waveform)) and (expectation adj (signal data information)) and (non\$volatile adj memory) and (circuit adj (block section part)) and (judge judgement judging)	IBM_TDB	OR	ON	2005/04/21 07:37
S110	1	(memory adj tester) and ((test testing) adj (signal data information waveform)) and (expectation adj (signal data information)) and (non\$volatile adj memory) and (circuit adj (block section part)) and (judge judgement judging)	US-PGPUB; USPAT	OR	ON	2005/04/21 07:37
S111	4	(memory adj tester) and ((test testing) adj (signal data information waveform)) and (non\$volatile adj memory) and (circuit adj (block section part)) and (judge judgement judging)	US-PGPUB; USPAT	OR	ON	2005/04/21 10:51
S112	1	((stor\$3 near3 (test adj (data information))) with (non\$volatile adj memory)) and (judg\$ with microcomputer with (defective faulty failed flawed))	US-PGPUB; USPAT	OR	ON	2005/04/21 10:54